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INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification 7 : H03K 17/66, G01R 31/319, H03K 5/24, 5/003, 19/00, 19/003, 19/082, 19/018	A2	(11) International Publication Number: WO 00/49715 (43) International Publication Date: 24 August 2000 (24.08.00)
(21) International Application Number: PCT/US00/04454 (22) International Filing Date: 18 February 2000 (18.02.00) (30) Priority Data: 09/253,175 19 February 1999 (19.02.99) US (71) Applicant: TERADYNE, INC. [US/US]; 321 Harrison Avenue, Boston, MA 02118 (US). (72) Inventor: BREGER, Peter; 4155 Vicasa Drive, Calabasas, CA 91302 (US). (74) Agent: WALSH, Edmund, J.; Teradyne, Inc., 321 Harrison Avenue, Boston, MA 02118 (US).	(81) Designated States: JP, KR, <u>SG</u> , European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE). Published Without international search report and to be republished upon receipt of that report.	

(54) Title: SERIAL SWITCH DRIVER ARCHITECTURE FOR AUTOMATIC TEST EQUIPMENT**(57) Abstract**

A tristate circuit for driving three signal levels to a pin of a device-under-test is disclosed. The tristate circuit includes a driver having an output at a first signal level and adapted for coupling to the pin. A first switching unit couples to the output and responds to a programmed signal. The first switching unit operates to selectively alter the first signal level to a second signal level. A second switching unit connects serially to the first switch. The second switching unit responds to a second programmed signal and operates to cooperate with the first switch to alter the second signal level to a third signal level.

